Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/617,813	CHANG, JAE WON
Examiner	Art Unit

Rita R. Patel

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Class	Subclass	Date	Examiner
68	12.01	4/10/2006	RRP
68	12.06	4/10/2006	RRP
68	23.1,	4/11/2006	RRP
68	23.2	4/11/2006	RRP
68	23.3	4/11/2006	RRP

INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
1				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor search.	4/10/2006	RRP		
EAST key word search.	4/11/2006	RRP		
Examiner F. Stinson; refined Class/Subclass search.	4/11/2006	RRP		
Refreshed class/subelass search.	6128/06	RRP		